Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination LU ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|-----|---|-----------------|-----------------------|----------------|
| | Α | US-6,568,098 | 05-2003 | Beckhart et al. | 33/645 |
| | В | US-6,436,726 | 08-2002 | Look et al. | 438/17 |
| | С | US-6,357,131 | 03-2002 | Cheng et al. | 33/645 |
| | D | US-6,339,730 | 01-2002 | Matsushima, Keiichi | 700/218 |
| | E | US-6,301,798 | 10-2001 | Liu et al. | 33/645 |
| | F | US-6,242,318 | 06-2001 | Mugibayashi et al. | 438/401 |
| | G | US-6,180,424 | 01-2001 | Tigelaar et al. | 438/14 |
| | Н | US-6,177,330 | 01-2001 | Yasuda, Tsuneo | 438/401 |
| | , 1 | US-5,929,529 | 07-1999 | Takizawa, Atsushi | 257/797 |
| | J | US-5,696,835 | 12-1997 | Hennessey et al. | 382/141 |
| | К | US-5,452,521 | 09-1995 | Niewmierzycki, Leszek | 33/520 |
| | L | US-4,635,373 | 01-1987 | Miyazaki et al. | 33/645 |
| | М | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
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NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | w | |
| | х | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.